

MOSFET - Power, Dual, N-Channel, Power Clip, POWERTRENCH®, Asymmetric 25 V NTMFD1D1N02X

Features

- Small Footprint (5x6mm) for Compact Design
- Low R_{DS(on)} to Minimize Conduction Losses
- Low Q_G and Capacitance to Minimize Driver Losses
- These are Pb-free, Halogen Free / BFR Free and are RoHS Compliant

Typical Applications

- DC-DC Converters
- System Voltage Rails

MAXIMUM RATINGS (T.I = 25°C unless otherwise stated)

Paran	neter		Sym- bol	Q1	Q2	Unit	
Drain-to-Source Voltag	je		V_{DSS}	25	25	V	
Gate-to-Source Voltag	е		V_{GS}	+16V -12V	+16V -12V	V	
Continuous Drain Cur-	Steady	T _C = 25°C	I _D	75	178	Α	
rent R _{θJC} (Note 3)	State	T _C = 85°C		54	128		
Power Dissipation $R_{\theta JC}$ (Note 3)		T _C = 25°C	P _D	27	44	W	
Continuous Drain Cur-	Steady	T _A = 25°C	I _D	20	40	Α	
rent R _{θJA} (Notes 1, 3)	State	T _A = 85°C		15	29		
Power Dissipation $R_{\theta JA}$ (Notes 1, 3)		T _A = 25°C	P _D	2.1	2.3	W	
Continuous Drain Cur-	Steady	T _A = 25°C	I _D	14	27	Α	
rent $R_{\theta JA}$ (Notes 2, 3)	State	T _A = 85°C		10	20		
Power Dissipation R _{θJA} (Notes 2, 3)		T _A = 25°C	P _D	0.96	1.0	W	
Pulsed Drain Current		= 25°C, : 100 μs	I _{DM}	331	625	Α	
Single Pulse Drain-to-Source Avalanche Energy Q1: I_L = 5.6 A_{pk} , L = 3 mH (Note 4) Q2: I_L = 13.6 A_{pk} , L = 3 mH (Note 4)			E _{AS}	47	277	mJ	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	-55 t	o 150	°C	
Lead Temperature Sold Soldering Purposes (1/8	TL	26	°C				

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

FET	V _{(BR)DSS}	R _{DS(on)} MAX	I _D MAX
Q1	25 V	3.0 mΩ @ 10 V	75 A
Q1	25 V	3.75 mΩ @ 4.5 V	75 A
00 05.1/		0.87 mΩ @ 10 V	
Q2	25 V	1.1 mΩ @ 4.5 V	178 A



PQFN8 POWER CLIP CASE 483AR

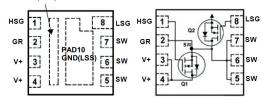
MARKING DIAGRAM

O NTMFD1 D1N02X AWLYWW

NTMFD1D1N02X = Specific Device Code

A = Assembly Site
WL = Wafer Lot Number
Y = Year of Production
WW = Work Week Number

PAD9 V+(HSD) ELECTRICAL CONNECTION



ORDERING INFORMATION

	Device	Package	Shipping [†]		
١	NTMFD1D1N02X	PQFN8 (Pb-Free)	3000 / Tape & Reel		

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

Table 1. THERMAL RESISTANCE RATINGS

Parameter	Symbol	Q1 Max	Q2 Max	Units
Junction-to-Case - Steady State (Note 1, 3)	$R_{ heta JC}$	4.6	2.8	°C/W
Junction-to-Ambient - Steady State (Note 1, 3)	$R_{ heta JA}$	60	55	
Junction-to-Ambient - Steady State (Note 2, 3)	$R_{ heta JA}$	130	120	

- 1. Surface-mounted on FR4 board using 1 in² pad size, 2 oz Cu pad.
- 2. Surface-mounted on FR4 board using minimum pad size, 2 oz Cu pad.
- The entire application environment impacts the thermal resistance values shown. They are not constants and are only valid for the particular conditions noted. Actual continuous current will be limited by thermal & electro–mechanical application board design. R_{θCA} is determined by the user's board design.
- by the user's board design.

 4. Q1 100% UIS tested at L = 0.1 mH, I_{AS} = 17.4 A. Q2 100% UIS tested at L = 0.1 mH, I_{AS} = 42.5 A.

Table 2. ELECTRICAL CHARACTERISTICS (T_{.1} = 25°C unless otherwise stated)

Parameter	Symbol	Test Condition		FET	Min	Тур	Max	Unit
OFF CHARACTERISTICS		•						
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V, } I_D = 250 \mu\text{A}$		Q1	25			V
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	\	Q2	25			V
Drain-to-Source Breakdown Voltage	V _(BR) DSS	$V_{(BR)DSS}$ $I_D = 250 \mu A$, ref to 25°C		Q1		15		mV/°C
Temperature Coefficient	`/ŤJ	I _D = 250 μA, ref to 25°0	С	Q2		16		1
Zero Gate Voltage Drain Current	I _{DSS}	$V_{GS} = 0 \text{ V}, V_{DS} = 20 \text{ V}$	T _J = 25°C	Q1			10	μΑ
				Q2			10	1
			T _J = 125°C	Q1			100	μΑ
				Q2			100	
Gate-to-Source Leakage Current	v-to–Source Leakage Current $I_{GSS} = V_{DS} = 0 \text{ V}, V_{GS} = +16 \text{ V}/-12 \text{ V}$ $V_{DS} = 0 \text{ V}, V_{GS} = +16 \text{ V}/-12 \text{ V}$		Q1			±100	nA	
			Q2			±100	1	
ON CHARACTERISTICS (Note 5)	•							
Gate Threshold Voltage	V _{GS(TH)}	TH) $V_{GS} = V_{DS}, I_D = 240 \mu A$		Q1	1.2	1.6	2.1	V
		V _{GS} = V _{DS} , I _D = 850 μA		Q2	1.2	1.6	2.1	
Threshold Temperature Coefficient	V _{GS(TH)} /	I _D = 240 μA, ref to 25°C		Q1		-4.0		mV/°C
	l J	I _D = 850 μA, ref to 25°C		Q2		-4.3		
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V, I _D = 20 A		Q1		2.4	3.0	mΩ
		V _{GS} = 4.5 V, I _D = 18 A				3.1	3.75	
		V _{GS} = 10 V, I _D = 37 A		Q2		0.66	0.87	1
		V _{GS} = 4.5 V, I _D = 33 A			0.68	0.84	1.1	1
Forward Transconductance	9FS	$V_{DS} = 5 \text{ V}, I_{D} = 20 \text{ A}$		Q1		123		S
		$V_{DS} = 5 \text{ V}, I_{D} = 37 \text{ A}$		Q2		322		
Gate Resistance	R _G	T _A = 25°C		Q1		0.8		Ω
				Q2		0.9		1

- 5. Pulse Test: pulse width $\leq 300~\mu\text{s}, \, \text{duty cycle} \leq 2\%$
- 6. Switching characteristics are independent of operating junction temperatures

Table 2. ELECTRICAL CHARACTERISTICS (T₁ = 25°C unless otherwise stated)

Parameter	Symbol	Test Condition	FET	Min	Тур	Max	Unit
CHARGES & CAPACITANCES	•						
Input Capacitance	C _{ISS}		Q1		1080		pF
			Q2		4265		
Output Capacitance	C _{OSS}	1	Q1		322		pF
		$V_{GS} = 0 \text{ V}, V_{DS} = 12 \text{ V}, f = 1 \text{ MHz}$	Q2		1020		
Reverse Capacitance	C _{RSS}	1	Q1		47		pF
			Q2		118		
Total Gate Charge	Q _{G(TOT)}		Q1		6.8		nC
			Q2		27		1
Gate-to-Drain Charge	Q_{GD}	Q1: V _{GS} = 4.5V, V _{DS} = 12V, I _D = 20A	Q1		1.4		nC
		Q2: $V_{GS} = 4.5V$, $V_{DS} = 12V$, $I_D = 37A$	Q2		5.2		
Gate-to-Source Charge	Q_{GS}]	Q1		3.0		nC
			Q2		11		
Total Gate Charge	Q _{G(TOT)}	Q1: V _{GS} = 10V, V _{DS} = 12V, I _D = 20A	Q1		15		nC
		Q2: $V_{GS} = 10V$, $V_{DS} = 12V$, $I_D = 37A$	Q2		59		
Output Charge	Q _{OSS}	V _{GS} = 0 V, V _{DS} = 12 V	Q1		6.2		nC
					22		1
Plateau Voltage	V_{GP}	Q1: V _{GS} = 4.5V, V _{DS} = 12V, I _D = 20A	Q1		2.8		V
		Q2: V _{GS} = 4.5V, V _{DS} = 12V, I _D = 37A			2.8		<u></u>
SWITCHING CHARACTERISTIC	S, VGS = 4.5 V (No	ote 6)					
Turn-On Delay Time	t _{d(ON)}		Q1		10		ns
			Q2		21		
Rise Time	t _{r(ON)}]	Q1		2.5		ns
		V _{GS} = 4.5 V	Q2		6.6		
Turn-Off Delay Time	t _{d(OFF)}	Q1: $I_D = 20 \text{ A}$, $V_{DD} = 12 \text{ V}$, $R_G = 2\Omega$ Q2: $I_D = 37 \text{ A}$, $V_{DD} = 12 \text{ V}$, $R_G = 2\Omega$	Q1		12		ns
		, b , bb , d	Q2		26		
Fall Time	t _f]	Q1		2.5		ns
			Q2		6.0		
SWITCHING CHARACTERISTIC	S, VGS = 10 V (No	te 6)					
Turn-On Delay Time	t _{d(ON)}		Q1		7.4		ns
			Q2		11		
Rise Time	t _{r(ON)}	Q1		1.1		ns	
		V _{GS} = 10 V	Q2		2.9		1
Turn-Off Delay Time	t _{d(OFF)}	Q1: $I_D = 20 \text{ A}$, $V_{DD} = 12 \text{ V}$, $R_G = 2\Omega$ Q2: $I_D = 37 \text{ A}$, $V_{DD} = 12 \text{ V}$, $R_G = 2\Omega$	Q1		17		ns
		. b , bb := 1,1.ig =	Q2		36		1
Fall Time	t _f	1	Q1		1.4		ns
			Q2		3.5		1

^{5.} Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2% 6. Switching characteristics are independent of operating junction temperatures

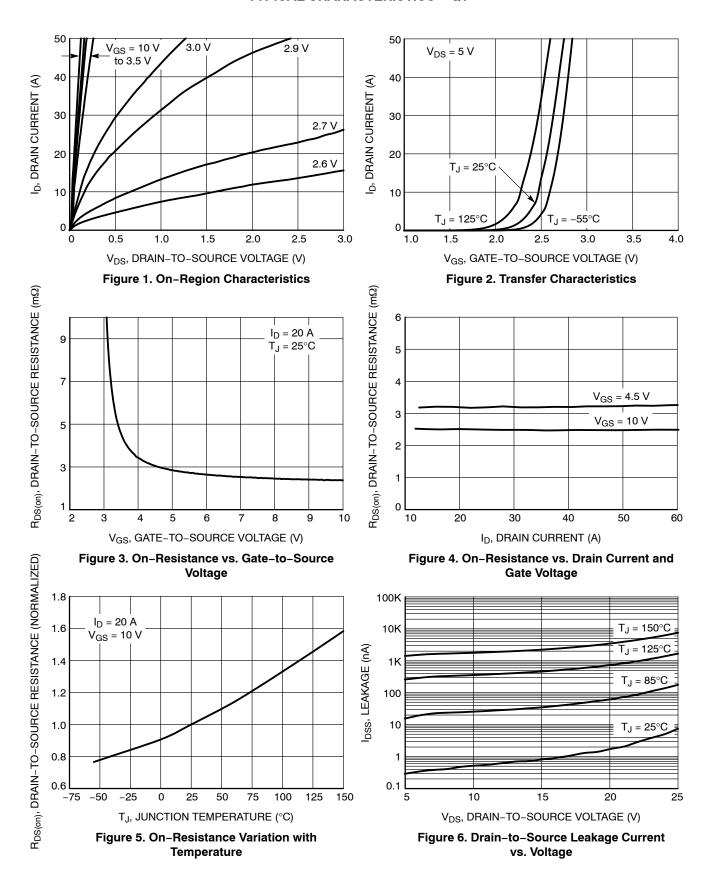
Table 2. ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise stated)

Parameter	Symbol	Test Condition		FET	Min	Тур	Max	Unit		
SOURCE-TO-DRAIN DIODE CHARACTERISTICS										
Forward Diode Voltage	V _{SD}	V _{GS} = 0 V, I _S = 20 A	T _J = 25°C	Q1		0.81		V		
			T _J = 125°C			0.68				
		V _{GS} = 0 V, I _S = 37 A	T _J = 25°C	Q2		0.8		1		
			T _J = 125°C			0.65		1		
Reverse Recovery Time	t _{RR}	V _{GS} = 0 V,	V _{GS} = 0 V,			18		ns		
		Q1: I _S = 20 A, dI/dt = 100 A/μs		Q2		35		1		
Reverse Recovery Charge	Q _{RR}	Q2: $I_S = 37 \text{ A}$, $dI/dt = 300 \text{ A}/\mu\text{s}$		Q1		6.6		nC		
				Q2		44		1		

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

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^{5.} Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2% 6. Switching characteristics are independent of operating junction temperatures



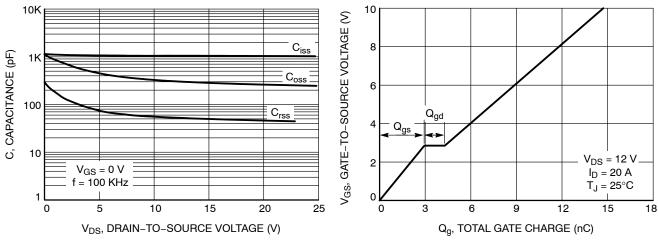


Figure 7. Capacitance Variation

Figure 8. Gate-to-Source vs. Total Charge

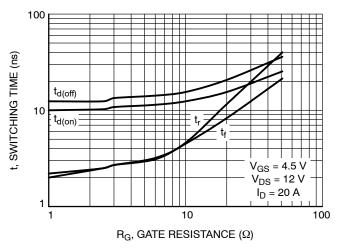


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

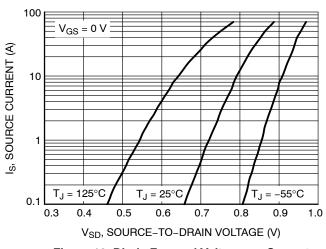


Figure 10. Diode Forward Voltage vs. Current

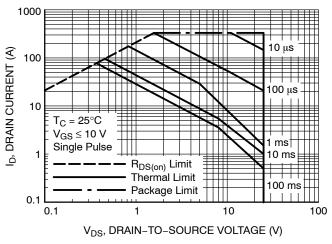


Figure 11. Maximum Rated Forward Biased Safe Operating Area

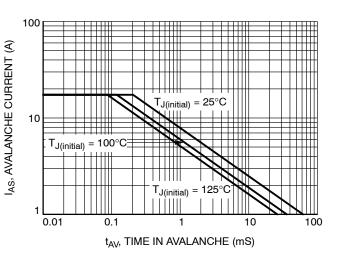


Figure 12. Avalanche Current vs. Time in Avalanche

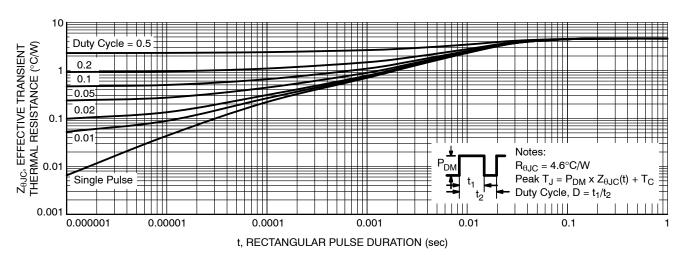
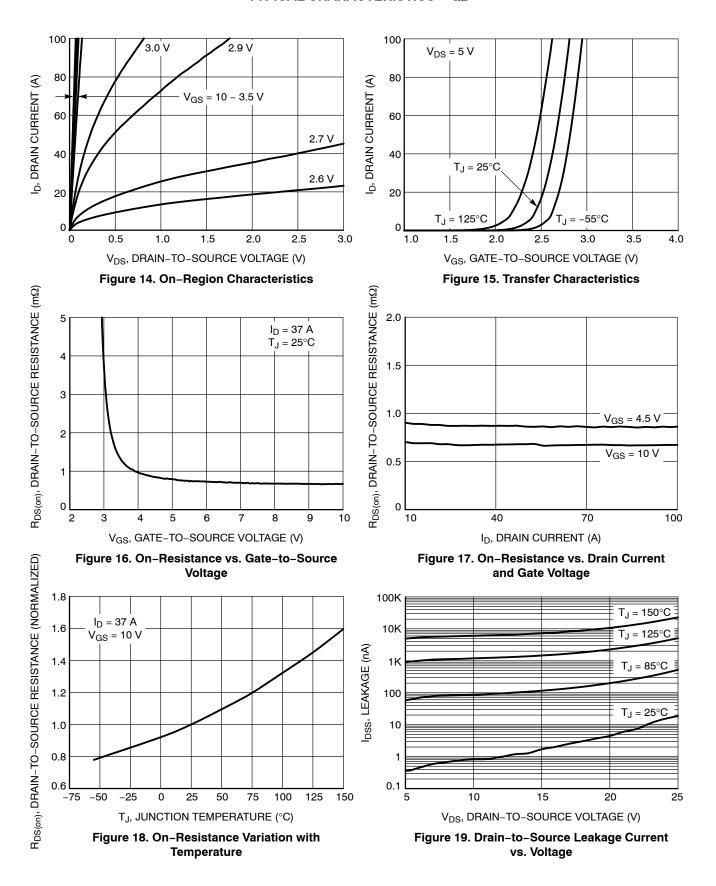


Figure 13. Transient Thermal Impedance



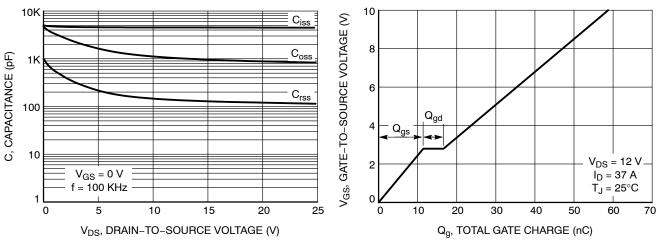


Figure 20. Capacitance Variation

Figure 21. Gate-to-Source vs. Total Charge

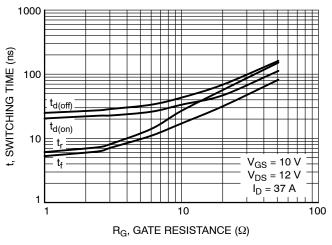


Figure 22. Resistive Switching Time Variation vs. Gate Resistance

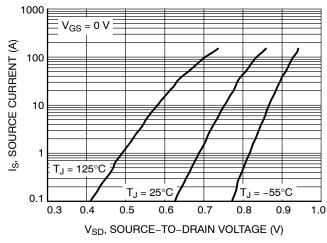


Figure 23. Diode Forward Voltage vs. Current

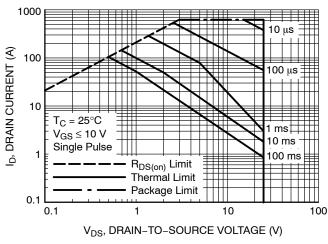


Figure 24. Maximum Rated Forward Biased Safe Operating Area

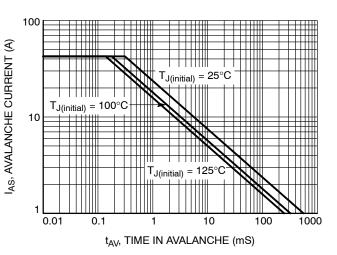


Figure 25. Avalanche Current vs. Time in Avalanche

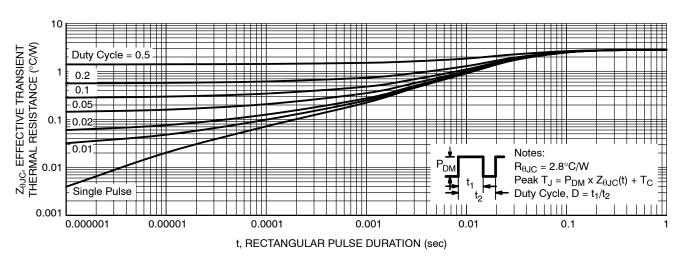
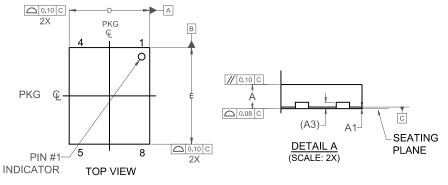


Figure 26. Transient Thermal Impedance

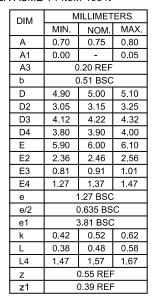
PACKAGE DIMENSIONS

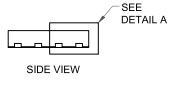
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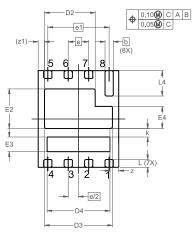


NOTES: UNLESS OTHERWISE SPECIFIED

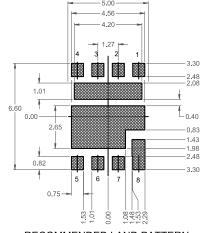
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- D) DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.







BOTTOM VIEW



RECOMMENDED LAND PATTERN

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